Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/719,484	CHEN ET AL.	
Examiner	Art Unit	_
David F Martinez	2181	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East see attached	8/16/2006	DM N
Inventor Search eDan	8/16/2006	DM
710/15-19,29,36-38.ccls. 709/217- 219,223-226,238-239.ccls. 370/248,329.ccls. with keywords and text search	8/16/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	8/16/2006	DM
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